

**Notice of References Cited**

Application/Control No.

10/585,484

Applicant(s)/Patent Under

Reexamination

VAN DE WEIJER ET AL.

Examiner

BRIAN R. SLAWSKI

Art Unit

1791

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
A	US-			
B	US-			
C	US-			
D	US-			
E	US-			
F	US-			
G	US-			
H	US-			
I	US-			
J	US-			
K	US-			
L	US-			
M	US-			

**FOREIGN PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N	JP 53005284 A	01-1978	Japan	IWAO, OSAMU	B32B 15/08
O	JP 11138738 A	05-1999	Japan	YOSHIDA et al.	B41C 1/14
P	JP 51098779 A	08-1976	Japan	YANASE	B29C 17/10
Q					
R					
S					
T					

**NON-PATENT DOCUMENTS**

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
U	
V	
W	
X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a))  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.